

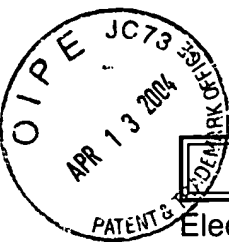
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Electronic Patent Application Submission  
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EFS ID: 58915  
Application ID: 10725744  
Title of Invention: SYSTEMS FOR INSPECTING  
WAFERS AND RETICLES WITH  
INCREASED RESOLUTION  
First Named Inventor: Steven Lange  
Domestic/Foreign Application: Domestic Application  
Filing Date: 2003-12-02  
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Statement  
Filing Type:  
Confirmation number: 3066  
Attorney Docket Number: 5589-05201




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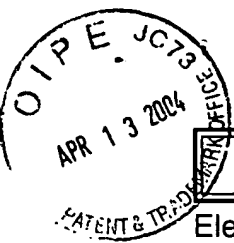
Digital Certificate Holder: cn=Kevin L. Daffer,ou=Registered Attorneys,ou=Patent and Trademark  
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Electronic Version v1.1  
Stylesheet Version v1.1.0

Title of Invention	SYSTEMS FOR INSPECTING WAFERS AND RETICLES WITH INCREASED RESOLUTION									
<div>Application Number: 10/725744 </div> <div>Date: 2003-12-02</div> <div>First Named Applicant: Steven R. Lange</div> <div>Confirmation Number: 3066</div> <div>Attorney Docket Number: 5589-05201</div>										
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Submitted by:	Elec. Sign.	Sign. Capacity								
Kevin L. Daffer Registered Number: 34146	Kevin L. Daffer	Attorney								
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Documents being submitted	Files									
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	us-ids.dtd									
	us-ids.xsl									
Comments										



# ELECTRONIC INFORMATION DISCLOSURE STATEMENT

Electronic Version v18

Stylesheet Version v18.0

Title of  
Invention

SYSTEMS FOR INSPECTING WAFERS AND RETICLES  
WITH INCREASED RESOLUTION

Application Number: 10/725744



Confirmation Number: 3066

First Named Applicant: Steven Lange

Attorney Docket Number: 5589-05201

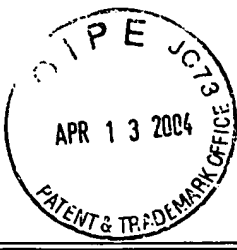
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or 4544626 or 4509852 or 5023424 or 5900354  
or 5004307 or 5121256 ).pn.

## US Patent Documents

Note: Applicant is not required to submit a paper copy of cited US Patent Documents

init	Cite.No.	Patent No.	Date	Patentee	Kind	Class	Subclass
	1	5825043	1998-10-20	Suwa			
	2	6191429	2001-02-20	Suwa			
	3	5298939	1994-03-29	Swanson et al.			
	4	4346164	1982-08-24	Tabarelli et al.			
	5	6493156	2002-12-10	Oh et al.			
	6	5610683	1997-03-11	Takahashi			
	7	5040020	1991-08-13	Rauschenbach et al.			
	8	4898804	1990-02-06	Rauschenbach et al.			
	9	4544626	1985-10-01	Sullivan			
	10	4509852	1985-04-09	Tabarelli et al.			
	11	5023424	1991-06-11	Vaught			
	12	5900354	1999-05-04	Batchelder			
	13	5004307	1991-04-02	Kino et al.			
	14	5121256	1992-06-09	Corle et al.			

Signature



Examiner Name	Date